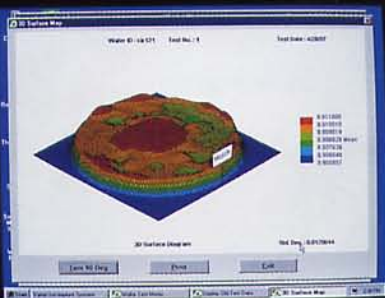
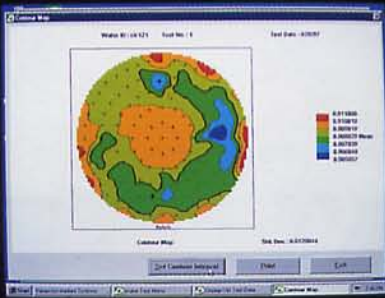




FOUR DIMENSIONS

# FOUR-POINT PROBE AUTOMATIC SYSTEM MODEL 300



## MAIN FEATURES

- Test Wafer Saving Features Available.
- Minimized Testing Time.
- Extremely High Sheet Resistivity Measurement Capability Available.
- Windows 95 Software with Librarian Data Storage.
- Can Be Attached With a Robot in Mini-environment and with Different Cassette Systems, No Prealigner is Needed.
- The Wafer Under Test Is Kept Very Close To The Room Temperature.

## MODEL 300 AUTOMATIC FOUR-POINT PROBE SYSTEM

### Not Just For 300mm Wafers

The probe station is 22.8"W, 27.9"D and 15"H in size. It can test a 6", 8" or 12" full or partial wafer as well as flat panel without computer control. Attaching it with a the computer and the software will add much more capability. The computer can be of any version or size as long as it is a PC.

### Most Powerful and Friendly

Everyone having had a chance to use our software admits that it is very straight forward to use. It has programs for contour mapping, 3D mapping, custom sites measurement, diameter scan, trend chart, SPC, data comparison with different formulas, spread sheet, LAN, SECSII, Librarian data storage and management, data backup, data delete (one by one or group by group), map crosssectioning, detail data tracing from trend chart, determining and editing temperature coefficient, automatic temperature compensation, repeatability test, push-button calibration, doing diagnostic for the probe station and many others, in Windows 95.

### Wide Range of Measurement Ability

It can test very thick wafer, such as slug, as well as very thin layer on a wafer or a rectangular plate without requiring mechanical adjustment. It can measure high resistivity sample such as intrinsic Si wafer as well as very low resistivity sample such as metal film. By performing an additional set-up, undoped poly Si film can also be measured.

### Saves You \$Millions by Saving Test

Adding a set of extra hardware and software to the standard system will allow you to save test wafers. Please call us to discuss this feature.

### Cassette to Cassette System

Standard cassette to cassette system is equipped with Jenoptik Infab FIXLOAD<sup>90</sup> and Genmark Gencobot IV. Other cassette system can be adopted. Wafer alignment is done by our optic system. Stainless steel framed mini-environment enclosure can maintain class 0.01 in the robot chamber.

## SPECIFICATIONS

**Measurement Repeatability:** Normally less than 0.2%.

**Measurement Speed:** About one minute for 49 site measurements.

**Electrical Power:** 100V, 115V, or 230V, one phase, 50Hz to 60Hz, 500VA.

**Vacuum:** 20 in Hg min at 1 l/min or less.

**N<sub>2</sub>:** 60 psi, 5 l/min. minimum

**Probe Head:** Metal case, jewel guided.

**Measurement Range:** 1m $\Omega$ /sq to 800K $\Omega$ /sq or 1m $\Omega$ /sq to 8E11  $\Omega$ /sq.